Welcome to the Microscopy Buyers' Guide.

The guide is published in print and online at www.microscopy-today.com. For such a guide to be truly useful, it must be comprehensive. Thus, the editors have assembled an index identifying hundreds of products listed under more than 300 categories.

How to use this Guide:

Print version: (1) Look up the product category in the **Products and Services Index**.

- (2) View the product descriptions in the **Microscopy Product Vendors** section.
- (3) Ascertain the company's scope at the **Company Profile** section.
- (4) View more complete product descriptions at the company website.

Online version: (1) Go to www.microscopy-today.com.

- (2) Click on "Buyers' Guide."
- (3) View an exact replica of the Buyers' Guide, or use the search box to find a particular kind of product.

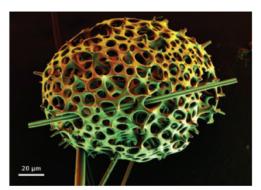
To companies not listed in this guide:

To list your company and promote your products in our next edition, please contact Amy Reuter at areuter@mrvica.com or 856-768-9360.

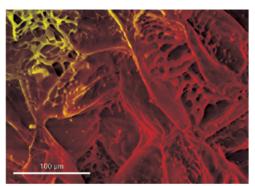
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Pseudo-color image of uncoated Radiolaria at 1 keV landing energy using beam deceleration technology. Sample courtesy of the University of Cambridge.



Thin slice of apple imaged on EVO LS with the EPSE detector at 20 kV and 100 Pa water vapor at -15 °C.

The EVO SEM by ZEISS captures exceptionally fine surface details with crisp contrast using a low-kV high definition backscattered electron detector (HD BSD). For beam sensitive samples or samples with surface topographies, beam deceleration technology achieves higher resolution and enhanced surface detail. Observe nano scale interactions of life science and materials samples at different temperatures, pressures and humidities.



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